

BIST-BASED GROUP TESTING FOR DIAGNOSIS OF EMBEDDED FPGA CORES

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Abstract— A group testing-based BIST technique to identify faulty hard cores in FPGA devices is presented. The method provides for isolation of faults in embedded cores as demonstrated by experiments on the Virtex-5 family of Xilinx FPGAs. High-level HDL code is developed to instantiate a Finite State Machine (FSM) which generates the test inputs for the Blocks Under Test (BUTs). The BUTs are divided into groups of four and at the end of a single stage of testing, up to 2 faulty BUTs are isolated successfully in each group of four. Experiments conducted show efficient fault isolation with a maximum of 30% area overhead under testing conditions. Isolation of faulty DSP cores is rapidly achieved without any permanent area cost. The approach can be readily extended to other embedded cores such as Block RAMs and Multipliers, thus providing a fast, efficient technique for testing prior to System On a Programmable Chip (SoPC) implementation on state of the art SRAM FPGAs.

Keywords: Embedded Cores, SOPC, FPGA Testing, Group Testing, DSP Hard Cores.

1. INTRODUCTION

The current generation of 65 nm FPGAs by Xilinx, such as the Virtex-5 platform FPGAs introduce space-efficient hard IP cores implemented using the column-based *Application Specific Modular Block (ASMBL)* architecture. The Virtex-5 platform provides anywhere from 32 to 640 embedded DSP48E cores across a range of devices [1]. These cores are designed, placed and routed into the fabric of the FPGA, and have been characterized and verified to optimize performance. Unlike soft IP cores, these enable designers to save the *Configurable Logic Blocks (CLBs)* as general-purpose logic resources and minimize the space and power required to implement diverse applications, including DSP applications on FPGAs. The embedded IP cores are characterized by their predictable timing and are optimized to work efficiently in a manner independent of the rest of the design. These cores are highly

customizable based on the designers' requirements and provide a range of in-built structures for efficient arithmetic calculation and signal processing requirements. All these characteristics lend to more efficient implementation of an entire system on an FPGA known commonly as a *System On Programmable Chip (SOPC)*. The development of FPGAs with an increasing number of embedded hard IP cores drives the need for faster testing methods for failures in the cores.

Since the embedded cores are numerous and distributed throughout the FPGA fabric as an integral part of the computational resources, they require extensive post-manufacturing testing and verification. Hence it is important to develop efficient testing methods to identify hardware faults with minimal latency and resource overheads. This article presents a *Built-In Self Test (BIST)* based approach that improves on previous techniques using a single-stage non-adaptive group testing algorithm to isolate defective embedded cores. Section 2 describes the previous work in testing FPGAs using BIST and BIST-inspired methods. Section 3 describes the group-testing based algorithm for fast isolation of faulty embedded cores, and Section 4 provides details from experiments conducted on the Virtex-5 family of devices. Finally, Section 5 completes the article by identifying areas for improvement and providing concluding remarks.

2. BACKGROUND

High device component density along with the trend toward high clock frequency and low power consumption present challenges for conventional methods of testing FPGAs. Advances in FPGA production technologies have improved capabilities to the point where FPGAs have dedicated embedded cores, including DSP cores and Block RAMs[1]. The most widely utilized approach to detect faults at the chip level in VLSI is to apply BIST at the component level [3,4,5]. The built-in nature of BIST also allows testing the chip in a variety of working environments. In BIST both the *Test Pattern Generation (TPG)* and *Output Response Analyzer (ORA)* are incorporated inside the device. Assuming that all levels of the hierarchy use BIST, each element can test itself and transmits the result to the succeeding level in the hierarchy. BIST also increases controllability and

observability by providing access to the internal nodes since tester logic is located on the chip. BIST allows tests to be run at system speed and eliminates this gap.

BIST has been the choice of convention for testing Embedded Memory [3, 4]. Conventional ASIC BIST techniques typically accrue between 10% to 30% area overhead and delay penalties [5]. Therefore, it is essential that the FPGA core test method leverages the reprogrammability inherent in FPGAs. An additional advantage of utilizing the programmable feature of an FPGA to test itself is that BIST logic can be removed when the circuit is reconfigured for another use and testability is achieved without permanent area overhead or performance degradation.

There has been considerable research on developing BIST techniques for programmable logic resources in an FPGA including CLBs [6,7,8] and interconnect matrix of routing resources [9,10,11]. Abramovici and Stroud [6] presented a BIST architecture to test CLBs in an FPGA. In their scheme, a column or row of CLB is configured to generate pseudo-exhaustive test patterns to alternating columns of identically configured CLBs under test. They use two identical TPGs to detect any fault in the CLBs used to construct TPGs. Comparator-based ORAs monitor the output of the BUTs and latch mismatches due to faults. The BUTs are tested and configured for different modes of operation. Each testing session covers only half of the CLBs and another session is required to test the other half.

The diagnostic procedure called *MULTICELLO* (Multiple faulty Cell Locator) developed by Abramovici et al., identifies faulty BUTs based on the failing BIST results. Stroud and Garimella [12] targeted multiple regular structure cores including memories and multipliers and developed a diagnostic procedure based on the extension of the *MULTICELLO* algorithm. The diagnostic procedure is performed in five steps described in [12]. They presented a BIST approach in which neighboring blocks are compared by a set of ORAs. Thus, each core is observed by two sets of ORAs and is compared to two different cores. Circular comparison of the first and last block covers the corner block. Following and applying the *MULTICELLO* algorithm, Garimella and Stroud [13] presented development of an automated BIST generation for embedded Block RAMs in an FPGA, based on parameterized VHDL model. The *MULTICELLO* algorithm provides a good diagnostic resolution and is able to locate the faulty blocks (unless all blocks have equivalent faults). However, it is not applicable when testing a set of two blocks in cascade mode. For example, in many applications and operations it is required that two DSP blocks cascaded together to produce the final outputs. In this case, they produce different outputs and therefore it is not possible to compare the outputs of neighboring blocks.

Renovell et al. [14] present a method to test the LUT/RAM modules of FPGAs using a minimal number of test configurations by proposing an architecture with

N inputs and $2N$ memory cells. With a unique test configuration, they test a single module by extending conventional algorithms for testing SRAM modules such as the *March tests* [15]. They also propose a unique test configuration called *pseudo shift register*. In this method, the circuit operates as a shift register and the MATS++ algorithm is adapted to test the FPGA RAM modules. However this method is limited to the SRAM modules on the FPGA, or the LUTs operating in the SRAM mode. The work is further developed in [16] which deals with testing logic cells, interconnect cells and RAM cell, using a minimal number of test configurations and test vectors.

Recently *Combinatorial Group Testing* techniques have begun to be applied to BIST based diagnosis [17,20]. The fundamental problem in group testing is to identify the subset of defective members, $\mathbf{D} \subset \mathbf{R}$, where \mathbf{R} is the set of all resources, using a minimal number of tests, t , on g groups which are subsets of \mathbf{R} . A group testing algorithm is *adaptive* if the tests are conducted in *stages* where the tests in later stages are based on the results of previous stages and *non-adaptive* otherwise. Fault location with very high precision can be achieved by integrating group testing methods such as *batching*, *digging*, *jumping*, and *doubling* with scan-based BIST on selected benchmark circuits. These methods can be used in conjunction with the techniques presented here to extend fault isolation coverage to the CLBs on the FPGA, in addition to the embedded IP cores.

Current state-of-the-art FPGAs such as the Virtex-5 DSP FPGAs from Xilinx offer embedded SoPC DSP modules that include dedicated two-input 25×18 multipliers followed by multiplexers and a three- input adder/subtractor/accumulator and dedicated DSP circuitry consisting of DSP48E slices[18].

In a previous effort, Sarvi *et al* [19] present a diagnostic method to detect and locate faulty embedded cores in FPGAs using BIST. The method partitions the cores on an FPGA into two groups and conducts BIST on each of these groups. The groups are created according to the following algorithm:

1. List all blocks in a target device in a set called L .
2. Count the number of blocks and label them from 0 through $n-1$.
3. Create two partitions (P_0 and P_1) of the set of blocks that have the following properties:
 - A. All members of the partitions are pairs of blocks. Note: This condition can only be satisfied if the number of blocks is even.
 - B. P_0 and P_1 block usage is mutually exclusive. In other words, there is no pair of blocks common in P_0 and P_1 .
4. Construct the partitions. Define partition P_0 as the set of pairs (i, j) from L , where i is even and $j = (i + 1) \bmod n$. Define partition P_1 as the set of pairs (q, r) from L , where q is odd and $r = (q + 1) \bmod n$.

Under this scheme the two configurations are constructed to enable isolation by comparison as shown in Figure 1, where 12 cores are shown in three possible configurations. Faulty blocks are indicated by an "x" mark whereas operational, fault-free blocks are indicated by a "√" mark. As shown in Figure 1(a) and Figure1(b) two sets of partitions are created

and the outputs of the cores bordered by the dashed lines are compared for discrepancies. Post processing the results from the scan chain generates the list of fault embedded cores. However, the technique configures the device twice in order to complete fault isolation. This minimizes resource utilization and simplifies the post-processing procedure. However, this method fails to isolate faulty blocks when there is a defective block in each of the compared pairs.

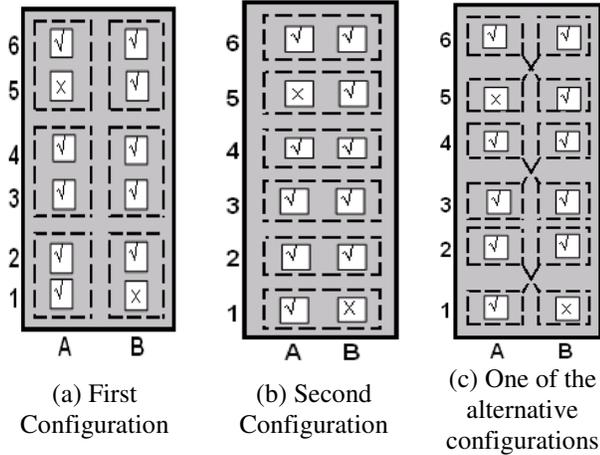


Figure 1. Logic BIST Architecture for Isolation Faulty Cores using Two Alternative Configurations

This paper extends the technique to an automated diagnostic methodology that is applicable to different cores, including DSP cores, that takes into account the different modes of operation. The method is scalable to different FPGA families including the Xilinx XtremeDSP products and the Virtex-5 family of FPGAs. Further, these techniques can be readily adapted to provide testing coverage for new families of embedded cores on FPGAs since the method is core-independent. A significant improvement is the one-shot testing of all embedded cores of a specified type using a single test pattern. Group testing techniques are utilized to generate a non-adaptive testing regimen that involves a single group of tests executed concurrently. The test provides complete coverage for all cores of a type on the chip by dividing the cores-under-test into subsets with a cardinality of four. By generating, comparing, and encoding the outputs produced by the cores in response to the test pattern, complete fault resolution is achieved in a single test.

3. GROUP TESTING-BASED BIST FOR ISOLATING FAULTY CORES

The embedded IP cores in the Xilinx Virtex-5 family of devices are distributed throughout the fabric ensuring optimal timing. The proposed BIST technique utilizes the CLBs adjacent to the embedded cores to realize the TPG and the ORA. Each embedded core comprises a

BUT. The current generation of Virtex-5 FPGAs from Xilinx includes embedded cores in the form of 36-Kbit Block dual-port Block RAMs and Advanced DSP48E slices. The DSP48E slices provide a range of functionality such as two's complement, multiplication, and optional adder, subtracter, and accumulator. These also provide pipelining and dedicated cascade connections. The number of DSP48E slices in the Virtex-5 FPGAs varies from 32 in the XC5VLX30 device to 640 in the XC5VVSX95T device. In the experiments described here, the DSP48E slices are the blocks under test.

Under the proposed group testing-based technique, the m embedded cores on the device are divided into $m/4 = n$ groups of BUTs. Tests are conducted on these groups to provide fault isolation in a *single-stage, non-adaptive* group testing regimen. Comparators k_n generate a *PASS/FAIL* result based on discrepancies between the outputs of two of the BUTs. For a group of 4 BUTs, a total of six comparators are required to compare each BUT's output with that of all the other BUTs in the same group. For purposes of simplicity, Figure 2 shows the replicable BIST model in its smallest scale, considering one such group of 4 BUTs, numbered B_0 through B_3 . It is assumed that the CLBs and routing resources have been tested for correct functionality.

The TPG is realized using an FSM to generate the states required for testing the embedded cores. In order to test the DSP48E cores, the FSM generates approximately 400 states and 14-bit wide control signals for each state. Each state defines a valid combination of control signals. The control signal bits are comprised of a 7-bit *opmode* signal, a 3-bit *carryin_sel* signal, and a 4-bit wide *alumode* signal. These serve as control inputs to each of the DSP48E embedded cores. For each of the 400 states, the FSM generates valid combinations of these 14 control signals which define the function implemented on the DSP48E at any given clock signal. The FSM is optimized via XST into one 512x14 ROM and a 14-bit registered output. This ROM is realized on one of the embedded BRAM cores which is pre-defined through initialization. State-transitions are performed via a 9-bit adder, whose output is registered using a 9-bit register. The three data operands for the DSP48E cores are generated using one 18-bit *Linear Feedback Shift Register (LFSR)*, one 48-bit LFSR and one 30-bit LFSR.

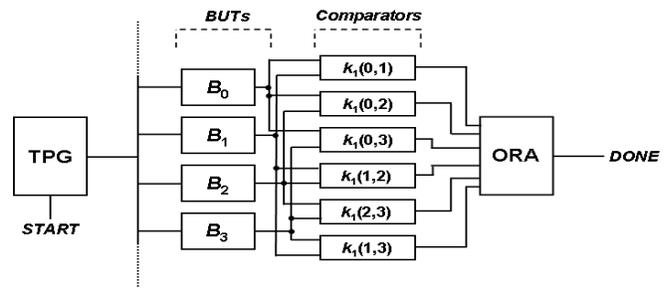


Figure 2. BIST Structure for Testing a Group of Four Blocks Under Test

Each pair of BUTs requires a 48-bit comparator and 4 1-bit comparators for their outputs to be compared for discrepancies. Each comparator contains the value 0xFF to register any mismatch. In addition to these, for each pair of

Table 1: Resource Utilization Results from Experiments Conducted on the Xilinx Virtex-5 Family of FPGAs

Device	DSP48E	Available Slices	Available LUTs	Available FFs	Resource Utilization under Test (Percentage)	
					LUTs	Flip flops
XC5VLX30	32	4800	19200	19200	1,418 (7%)	384 (2%)
XC5VLX50	48	7200	28800	28800	1862 (6%)	408 (1%)
XC5VLX85	48	12960	51840	51840	1862 (6%)	408 (1%)
XC5VLX110	64	17280	69120	69120	2300 (3%)	432 (1%)
XC5VLX155	128	24320	97280	97280	4058 (4%)	528 (1%)
XC5VLX220	128	34560	138240	138240	4058 (2%)	528 (1%)
XC5VLX330	192	51840	207360	207360	5822 (2%)	624 (1%)
XC5VSX35T	192	5440	21760	21760	5822 (26%)	624 (2%)
XC5VSX50T	288	8160	32640	32640	8462 (25%)	768 (2%)
XC5VSX95T	640	14720	58880	58880	18139 (30%)	1296 (2%)

BUTs, a 2x1 multiplexer is used to serialize the results of the comparators. Thus for every group of BUTs, a total of six 2x1 multiplexers are required. This circuitry is further optimized as described in the following section. Figure 2 shows these six comparators $k_i(i,j)$ for comparing the outputs of the 4 BUTs in group $n = 1$. The technique uses a test controller in addition to the TPG and the ORA, to activate the test routine by asserting the START signal. Termination of the test is achieved when the DONE signal is asserted, followed by the propagation of the test results.

It is highly unlikely that two compared blocks have identical defects and consequently the comparison of their outputs for a particular test state results in a match. In this case, from post-processing results, it can be determined that there are two faulty blocks with identical failures in a group of four. To isolate the failures into individual blocks in these rare cases, at the very last clock cycle of the test, the output of each DSP can be compared against an expected data known as a signature. The signature can be in form of *Multi-Input Signature Register* (MISR) or adder/accumulator or other forms of well-known signature analyzer. In the case of DSP, portion of the output of DSP can be fed back to its input and the last result can be used as a signature. Utilizing only these forms of signature analyzers without comparators is not sufficient for fault isolation and detection as it is possible that a faulty unit generates the same signature as a functional unit and so error is masked. Comparing the results at each clock cycle ensures that these defective blocks (masked in MISR for example) don't go undetected. Additionally, the signature can be generated via simulation off-line. Enhancing the methodologies to include signature response analyzer also enables us to detect even more than two defective blocks in each group of four.

4. FAULT ISOLATION EXPERIMENTS ON Virtex-5 FPGAs

As a particular example of the BIST technique, experiments were conducted on the Virtex-5 family of Xilinx FPGAs. The testing of an XC5VLX30 device

provides the following case study which further elaborates the procedure. The XC5VLX30 device consists of 32 DSP48E embedded cores, with 4800 slices that provide 19200 LUTs. The $m = 32$ embedded cores on the XC5VLX30 device are divided into $n = 8$ groups. Since six 2-to-1 multiplexers are required for each group, a total of 48 such multiplexers are required. However, the synthesized design optimally uses six 8-to-1 multiplexers.

A block diagram of the scheme is shown in Figure 3. As shown in the figure, a total of six multiplexers and flip flops, numbered mux_0 through mux_5 and FF_0 through FF_5 are utilized. There are six columns of comparators, with each column consisting of eight comparators, k_0 through k_7 . Comparators $k_n(i,j), 0 \leq i,j \leq 3, \forall i \neq j$ complete the test for a group of four BUTs as shown in Figure 2. The results for comparisons among one group of BUTs, for example, the results from $k_0(0,1), k_0(0,2), k_0(0,3), k_0(1,2), k_0(1,3)$ and $k_0(2,3)$ are registered in the flip flops FF_0 through FF_5 . This is then repeated for the other groups, using the 3-bit counter to enable the succeeding inputs of each multiplexer. Thus, at the end of each test, when the inputs from the TPG have been applied, the counter goes through all the multiplexer inputs and sending the output of the six flip flops simultaneously to 6 single-bit outputs. The fault diagnosis script then processes the results of each set of 6 outputs to resolve the location of the defective BUTs. This leads to isolation of faults in any two of the four BUTs in each group, irrespective of the location of the faulty BUTs within each group, unlike the previous solution.

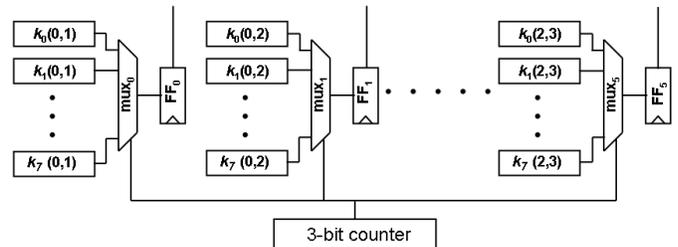


Figure 3. BIST Structure used for Testing the XC5VLX30 Device

Further, the solution was implemented on various devices of the Virtex-5 family with Xilinx ISE synthesis tool. Table 1 summarizes the resource usage for each of these devices. As listed in the Table, for the XC5V5X95T device, which contains 640 DSP48E embedded cores, the device utilization during testing is approximately 30%. In Table 1, all Utilization Percentage figures less than 1% have been rounded up to 1%. Also, each slice in the Virtex-5 family of FPGAs contains four 5-input LUTs and four flip flops.

4. CONCLUSION

Embedded cores within FPGAs provide improved performance by optimizing area and power consumption. With improvements in the process technology, the smaller geometries will drive the inclusion of an increasing number of diverse hard IP blocks in FPGAs. As shown in this article, the XC5V5X95T device in the Virtex-5 family contains 640 DSP cores and 488 Block RAM cores. This shows the need for efficient fault isolation techniques to diagnose these devices to improve yields and facilitate faster debugging. The demonstrated technique achieves the goal of fast detection and isolation of faults by leveraging a group testing technique that isolates faulty embedded cores in a single-step procedure that precludes the need for device reconfiguration. The approach is scalable at the cost of temporary area overhead. However, no permanent area cost or performance overheads are incurred as a result of testing. The presented technique can be used in conjunction with other existing methods for isolating faults in interconnect and CLBs to provide complete post-manufacturing testing for FPGAs with embedded cores. Additionally, the method is also suitable for periodic offline testing of embedded cores in operational devices.

6. REFERENCES

- [1] Xilinx, Inc., Virtex-5 Family Overview – LX, LXT, and SXT Platforms, December 2007.
- [2] Y. Zorian, E.J. Marinissen, S. Dey, "Testing Embedded-Core Based System Chips," Proceedings International Test Conference, pp. 130-141, 1998.
- [3] K. Saluja, S. Eng, and K. Kinoshita, "Built-In Self Testing of Embedded Memories," IEEE Design & Test of Computers, Oct. 1986, pp.27-37.
- [4] P. Camurati, P. Prinetto, M.S. Reorda, S. Barbagallo, A. Burri, D. Medina, "Industrial BIST of Embedded RAMs," IEEE Design & Test of Computers, Autumn/Fall 1995, Vol. 12 Issue 3, pp. 86.
- [5] C. Stroud, P. Chen, S. Konala, and M. Abramovici, "Built-in self-test for programmable logic blocks in FPGAs (finally, a free lunch: BIST without overhead!)," Proc. IEEE VLSI Test Symp., pp. 387-392, 1996.
- [6] M. Abramovici, C. Stroud, "BIST-Based Test and Diagnosis of FPGA Logic Blocks," IEEE Transactions on Very Large Scale Integration (VLSI) Systems, Vol.9, No.1, pp. 159-172, 2001.
- [7] E. Atoofian and Z. Nabavi, "A BIST Architecture for FPGA Look-Up Table Testing reduces Reconfiguration," Proceeding of the 12th Asian Test Symposium, pp. 84-89, 2003.
- [8] M. Niamat and P. Mohan, "Logic BIST architecture for FPGAs," Proceedings of the 44th IEEE Symposium on Circuits and Systems, Vol. 1, pp. 442 – 445, 2001.
- [9] J. Liu and S. Simmons, "BIST-Diagnosis of Interconnect Fault Locations in FPGAs," CCECE 2003.
- [10] A. Doumar and H. Ito, "Detecting, Diagnosing, and Tolerating Faults in SRAM-Based Field Programmable Gate Arrays: A Survey," IEEE Transactions on Very Large Scale Integration (VLSI) Systems, Vol.11, No.3, pp. 386-405, June 2003.
- [11] M. Renovell, J. M. Portal, J. Figueras, Y. Zorian, "Testing the Local Interconnect Resources of SRAM-Based FPGAs," Journal of Electronic Testing: Theory and Applications, Vol. 16, pp. 513, 520, 2000.
- [12] C. Stroud, S. Garimella, "Built-In Self-Test and Diagnosis of Multiple Embedded Cores in SoCs," Proceedings of The 2005 International Conference on Embedded Systems and Applications, ESA 2005, pp. 130-136, Las Vegas, Nevada, USA, June 2005.
- [13] S. Garimella, C. Stroud, "A system for Automated Built-In Self-Test of Embedded Memory Cores in System-on-Chip," Proceedings of the Thirty-Seventh Southeastern Symposium on System Theory, pp. 50-54, 2005.
- [14] M. Renovell, J. M. Portal, J. Figueras, Y. Zorian, "SRAM-Based FPGAs: Testing the Embedded RAM Modules," in Journal of Electronic Testing, Vol. 14, No.1-2, February 1999.
- [15] A.J. Van De Goor, "Using March Tests to Test SRAMs," IEEE Design and Test of Computers, Vol. 10, No. 1, January 1993.
- [16] M. Renovell, Y. Zorian, "Different Experiments in Test Generation for XILINX FPGAs," in Proceedings of the International test Conference, 2000, pp. 854.
- [17] A.B. Kahng AND S. Reda, "New and Improved BIST Diagnosis Methods from Combinatorial Group Testing Theory," IEEE Transactions on Computer-Aided Design, 25 (3), 2006, pp. 533-543.
- [18] Xilinx Inc., "Virtex-5 FPGA XtremeDSP Design Considerations," Available at http://www.xilinx.com/support/documentation/user_guides/ug193.pdf ., February 2008.
- [19] A. Sarvi, J. Fan, "Automated BIST-Based Diagnostic Solution For SOPC," IEEE International Conference on Design & Test of Integrated Systems in Nanoscale Technology, Sep 2006, pp.-263-267.
- [20] R. S. Oreifej, C. A. Sharma, R. F. DeMara, "Expediting GA-Based Evolution Using Group Testing Techniques for Reconfigurable Hardware," in Proceedings of the IEEE International Conference on Reconfigurable Computing and FPGAs (Reconfig'06), San Luis Potosi, Mexico, September 20-22, 2006, pp 106-113.